# Grain Boundary Ionic Conduction in Zirconia-based Solid Electrolyte with Alumina Addition\*

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## Abstract

The grain boundary resistance of 9 mol% Y<sub>2</sub>O<sub>3</sub>stabilized ZrO2 with Al2O3 addition was measured by the complex impedance approach. The effect of Al<sub>2</sub>O<sub>3</sub> addition on the grain boundary resistance was analyzed from the aspects of microstructure and crystal defects by means of SEM, EPMA, TEM and the positron annihilation technique. The  $Al_2O_3$ addition up to 5 mol\% was found to reduce the grain boundary resistance per unit surface area of the grain boundaries and the activation energy for the grain boundary resistance. This phenomenon was explained by the scavenging of the grain boundary impurities, e.g. SiO2, by the Al2O3 and the formation of the crystal grain boundary phases with very high defect concentration. By the analyses with a simplified theoretical model, the Al<sub>2</sub>O<sub>3</sub> addition was considered to have no detrimental effect on the emf of the ZrO2 oxygen sensor.

#### 1 Introduction

In polycrystal ceramic materials, grain boundaries have a large, often controlling importance for properties. The studies on grain boundary behavior are essential for the design of ceramic materials, and the control and optimization of their performances. Thus a concept of 'grain boundary engineering' was put forward, i.e. to improve the properties of ceramics by modifying grain boundaries. Now the grain boundaries of ZrO<sub>2</sub>-based solid electrolyte have attracted much attention.

As one of the most important solid electrolytes, much research has been performed on ZrO<sub>2</sub>.

Although the research results are not totally in keeping with each other, the following points have been clarified: (1) the grain resistivity of polycrystal ZrO<sub>2</sub> is equivalent to that of a single crystal, and it is usually not affected by sintering temperature, atmosphere and heat treatment;<sup>2</sup> (2) the efforts to reduce the grain resistivity by changing composition (e.g. adding Y<sub>2</sub>O<sub>3</sub>, CaO, MgO, rare earth oxides, and two, three or more oxides are simultaneously added) are now nearly exhausted, the optimum stabilizer concentrations, e.g. 8-9 mol% Y<sub>2</sub>O<sub>3</sub> or 13-14 mol% CaO have been generally established;3 it is difficult to find a new stabilizer which can remarkably reduce the grain resistivity in a expectable period; (3) the property and structure of grain boundary phases are strikingly influenced by impurity, sintering temperature, atmosphere and heat treatments;<sup>4</sup> (4) the ZrO<sub>2</sub> grain boundary resistivity may be lower or higher than that of grain due to the difference of segregated elements and variation of grain boundary structure.<sup>5,6</sup> All these points suggest that a feasible way to further enhance the ionic conduction of ZrO<sub>2</sub> is to reduce the grain boundary resistivity by adding a new kind of ingredient. In order to densify ZrO<sub>2</sub> during sintering, certain amounts of Al<sub>2</sub>O<sub>3</sub> were often added to ZrO<sub>2</sub>. After further study, it was discovered that Al<sub>2</sub>O<sub>3</sub> can also reduce the resistance of ZrO<sub>2</sub>.8 In this paper, Al<sub>2</sub>O<sub>3</sub> up to 5 mol% is added and the grain boundary resistance is studied.

# 2 Experimental Procedure

## 2.1 Preparation of specimens

The compositions of specimens are listed in Table 1. Powders used to produce the specimens were prepared from ZrOCl<sub>2</sub> · 8H<sub>2</sub>O, YCl<sub>3</sub> and AlCl<sub>3</sub> by

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Table 1. Compositions of specimens

Specimen	Composition		
0AYZ	ZrO <sub>2</sub> -9 mol% Y <sub>2</sub> O <sub>3</sub>		
1·5AYZ	$ZrO_2^2 = 9 \text{ mol}\%Y_2O_3 = 1.5 \text{ mol}\% \text{ Al}_2O_3$		
5AYZ	$ZrO_2^2 - 9 \text{ mol}\% Y_2O_3 - 5 \text{ mol}\% Al_2O_3^2$		

a coprecipitation method, average particle sizes measured by a centrifugal particle size analyzer (type SA-CP3) are 0.45  $\mu$ m, 0.40  $\mu$ m and 0.48  $\mu$ m respectively. The powders were subsequently pressed into pellets (22 mm in diameter by 4 mm thick) at 200 MPa, then sintered at 1600°C for 2 h. The platinum electrodes were applied to the ZrO<sub>2</sub> specimens by the decomposition of chloroplatinic acid at 1000°C.

#### 2.2 Measurements and analyses

The specimens under went the following measurements and analyses. (1) Resistances were measured by the complex impedance approach in a frequency range of 20 Hz to 1 MHz with a HP4285A precision LCR meter, the grain and grain boundary resistances were separated out by the analyses of the complex plots. (2) Al distribution information inside the specimens was examined by EPMA (type JCXA-733) on the specimens polished and coated with carbon. (3) Microstructure studies were carried out with SEM (type JSM-35C) and TEM (type H-800, Philips-CM<sub>12</sub>/STEM). (4) Crystal defect changes were detected by the positron annihilation technique (CANBERRA Series 35).

#### 3 Results

# 3.1 Grain boundary resistance

The complex impedance approach has been used extensively in the examination and development of solid electrolytes after the initial report by Bauerle. This approach can effectively probe the grain resistance as well as the resistance across grain boundaries and electrode/electrolyte interfaces.

The grain boundary resistances  $R_{\rm gb}$  of the specimens were measured at 440°C and 500°C; the results are listed in Table 2. In order to explain further the measured results, the grain boundary

resistances per unit surface area of grain boundaries  $R_{\rm gbs}$  were calculated from 10

$$R_{\rm gbs} = \rho_{\rm gb}/D = R_{\rm gb}(S/l)/D \tag{1}$$

where  $\rho_{\rm gb}$  is the grain boundary resistivity, S/l is the cross-section/length ratio of the specimen and D the grain boundary density.  $R_{\rm gbs}$  has been used before by Miyayama and coworkers to explain intrinsic and extrinsic grain boundary phenomena,8,10 because R<sub>gbs</sub> values contain no microstructural effects. The  $R_{\rm gbs}$  values are also listed in Table 2. For the case studied in this paper, if space charges resulting from the irregularity of lattice can account for the resistance of the grain boundary surface (intrinsic effect), the  $R_{\rm ebs}$  should be constant, i.e. independent of Al<sub>2</sub>O<sub>3</sub> content. However, for the extrinsic effects (impurity dominated), when the Al<sub>2</sub>O<sub>3</sub> addition increases, the concentration of Al<sub>2</sub>O<sub>3</sub> per unit surface area of grain boundaries also increases, notwithstanding the change of the grain boundary density D. Therefore, the  $R_{\rm gbs}$  should be affected by the Al<sub>2</sub>O<sub>3</sub> addition; this, in fact, is the case for the specimens used in this study. The  $R_{\rm gbs}$  of the specimen 0AYZ is much higher than those of the specimens 1.5AYZ and 5AYZ; the specimen 5AYZ has the smallest  $R_{\rm gbs}$  value.

Activation energies for the grain boundary resistance can be calculated from the Arrhenius equation

$$R = A \exp(E/KT) \tag{2}$$

where K and T have their usual meanings. The values are listed in Table 2. The specimen 0AYZ has the largest grain boundary resistance activation energy  $E_{\rm gb}$ , and  $E_{\rm gb}$  decreases with increasing Al<sub>2</sub>O<sub>3</sub> content.

#### 3.2 Positron annihilation

The measurements of positron lifetime spectra were carried out at room temperature  $(21 \pm 1)^{\circ}$ C by a fast-fast coincidence lifetime spectrometer with a resolution of 230ps. A <sup>22</sup>NaCl positron source was used in the measurements. A normal specimensource-specimen sandwich arrangement was adopted. A total of  $10^6$  counts in each spectrum were collected. After substracting the source and background contribution, all lifetime spectra were

Table 2. The grain boundary resistances and the activation energy of the specimens

g :	Measured at 440°C		Measured at 500°C		Activation energy	
Specimen	$R_{gb}(\Omega)$	$R_{gbs} (\Omega/cm^2)$	$R_{gb}(\Omega)$	$R_{gbs}$ $(\Omega/cm^2)$	$E_{gb}(kJ/mol)$	
0AYZ	1 400	6.5	300	1.4	117-6	
1.5AYZ	215	4.1	50	0.96	111-3	
5AYZ	175	1.2	50	0.35	95.6	

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Specimen	$\tau_l(ps)$	$\tau_2(ps)$	τ <sub>3</sub> (ps)	I <sub>1</sub> (%)	I <sub>2</sub> (%)	I <sub>3</sub> (%)	$K(\mu s^{-1})$
0AYZ	239	269	1 802	90.5	8.2	1.3	38.3
1-5 <b>AYZ</b>	205	353	1 685	90.5	7.6	1.5	155-4
5AYZ	204	375	1 806	92.0	6.9	1.2	153.7

**Table 3.** Positron lifetime parameters

analyzed with three components by the program POSITRONFIT EXTENDED. Lifetimes  $\tau_1$ ,  $\tau_2$  and  $\tau_3$  and their relative intensities  $I_1$ ,  $I_2$  and  $I_3$  were obtained (listed in Table 3). The long lifetime component  $\tau_3$ , whose intensity is about 1.4%, may arise from the positron annihilation in the positron source and associated foils, and/or interfaces that are unavoidable with the sandwich arrangement, so  $\tau_3$  will not be discussed. The short lifetime component  $\tau_1$  reflects the positron annihilation feature in perfect lattices, and  $\tau_2$  is the positron lifetime in crystal defects. According to the two-state trapping model, 11 the trapping rate of the defects to positron K can be derived,

$$K = I_2 / \left(\frac{1}{\tau_1} - \frac{1}{\tau_2}\right) \tag{3}$$

The K values are listed in Table 3. Because  $K = \mu C$ , where C is the concentration of defects and  $\mu$  is the specific trapping rate which can be con-

sidered as a constant when the type or structure of the defects does not change; thus the change of K can roughly reflect the change of the defect concentration. The K value increases when  $Al_2O_3$  is added to  $ZrO_2$ , this tendency is opposite to that of the grain boundary resistance per unit surface area of grain boundaries  $R_{\rm gbs}$ ; in other words, with increasing  $Al_2O_3$  content, the defect concentration of the specimens increases, and consequently the  $R_{\rm gbs}$  value decreases.

## 3.3 Microstructure

The solubility of  $Al_2O_3$  in  $ZrO_2$  grain is very low, only 0.5 mol%  $Al_2O_3$  can be dissolved in  $Y_2O_3$ -stabilized  $ZrO_2$  sintered at 1700°C and cooled at 220°C/h,8 and the solubility of  $Al_2O_3$  is about 0.1 mol% when sintered at 1300°C.12 So it is obvious that the  $Al_2O_3$  additions in the present work are far beyond the  $Al_2O_3$  solubility.

Figure 1 shows the scanning electron micro-

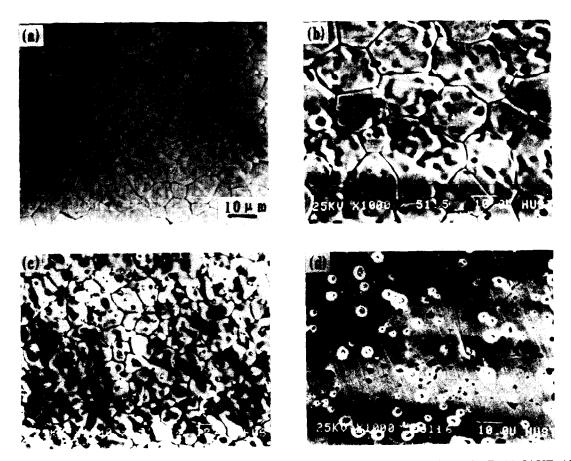


Fig. 1. Scanning electron micrographs of the surfaces of as-sintered specimens. (a) 0AYZ, (b) 1.5AYZ, (c) 5AYZ, (d) 1.5AYZ, polished surface.

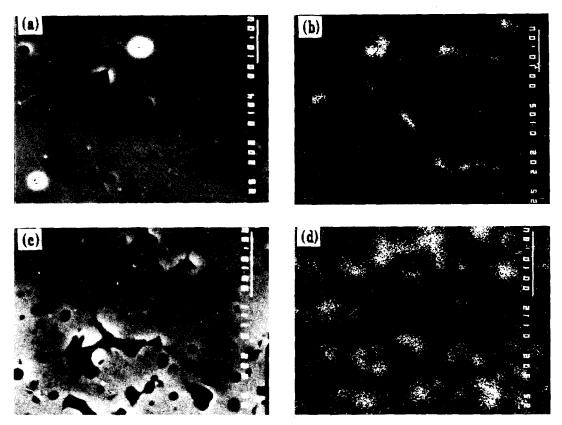


Fig. 2. EPMA photographs of the specimens with different Al<sub>2</sub>O<sub>3</sub> content. (a), (b) 1 5AYZ, (c), (d) 5AYZ.

graphs of the surfaces of the as-sintered specimens 0AYZ, 1.5AYZ and 5AYZ, and the polished surface of the specimen 1.5AYZ. The specimen 0AYZ has a homogeneous mono-phase structure, while Al<sub>2</sub>O<sub>3</sub> particles can be observed as bright or dark spots in the specimens 1.5AYZ and 5AYZ; the Al<sub>2</sub>O<sub>3</sub> particles are situated both inter- and intragranularly. Because there are quite large differences in the elastic modulus and the thermal expansion coefficient between Al<sub>2</sub>O<sub>3</sub> and ZrO<sub>2</sub>, the intragranular Al<sub>2</sub>O<sub>3</sub> particles are always accompanied by pores, which can be seen from the polished surface.

Figure 2 shows the EPMA analysis results, in which photographs (a) and (c) are scattered electron images and photographs (b) and (d) display the Al distributions. From these photographs, it can be seen that Al is mainly segregated at grain boundaries, and that the Al segregation is more serious in the specimen 5AYZ. Some small dark spots inside grains shown in the scattered electron images are Al<sub>2</sub>O<sub>3</sub> particles and pores. Apparent enrichment of Si and Ca at grain boundaries was not observed.

Because of the segregation of  $Al_2O_3$  and impurities at grain boundaries, grain boundary phases are often formed. Two types of grain boundary phases were discovered in the specimens with  $Al_2O_3$  addition; one type is shown in Fig. 3. The small bright particle situated at the triple point of  $ZrO_2$  grains is an  $Al_2O_3$  particle (Fig. 3(a)), the

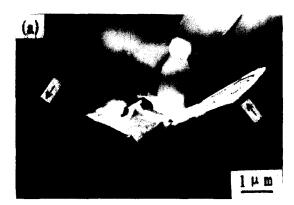
grain boundary phases have a peculiar morphology. Figure 3(b) is the SADP of the grain boundary phases, the diffraction rings indicate that the grain boundary phases consist of large amount of crystallites. The ratio of the square radii of the diffraction rings is

$$R_1^2: R_2^2: R_3^2: R_4^2: R_5^2: R_6^2 \approx 1:2:3:6:7:9$$
 (4)

According to the ratio and brightness distribution of the diffraction rings, these crystallites do not have crystal structure of α-Al<sub>2</sub>O<sub>3</sub> or cubic ZrO<sub>2</sub>; because of the large errors usually involved in electron diffractions, it is still difficult to determine the crystal structure of the crystallites. The composition of the grain boundary phases measured by EDAX is given in Table 4. An enrichment of Al was found and no impurities such as Si, Ca were detected. However, for the crystal grain boundary phases at different regions of the specimen, different SADP patterns are produced and different Al, Y and Zr concentrations are measured by EDAX. The phases may be con-

Table 4. Composition of the crystal grain boundary phases measured by EDAX

Element	wt%	at.%
Al	2.62	8.29
Y	15.76	15-17
Zr	81 62	76-54



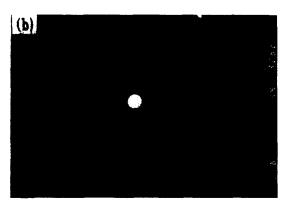


Fig. 3. Transmission electron micrographs of the crystal grain boundary phases. (a) Bright field image, (b) SADP. The arrows indicate the grain boundary phases.

cluded to be a kind of Al-rich compound with a chemical formula

$$(Al_2O_3)_x(Y_2O_3)_y(ZrO_2)_z(x + y + z = 1).$$

The amount of the crystal grain boundary phases is quite large; they are distributed at grain boundaries and Al<sub>2</sub>O<sub>3</sub>/ZrO<sub>2</sub> interfaces.

Another type of grain boundary phase is shown is Fig. 4. This type of grain boundary phase is rarely found in the specimens, they are distributed at triple points (Fig. 4(a)) and Al<sub>2</sub>O<sub>3</sub>/ZrO<sub>2</sub> interfaces (Fig. 4(b)). The SADP of the grain boundary phases (Fig. 4(c)) indicates that they are amorphous, and corresponding EDAX measurement (Table 5) discovers impurities Si and Ca, besides the enrichment of Al. The grain boundaries without amorphous phases are quite clean, no impurities such as Si and Ca are presented there.

According to these analyses, it can be concluded that there are three forms of Al<sub>2</sub>O<sub>3</sub> in existence in ZrO<sub>2</sub>. They are: (1) a very small amount of Al<sub>2</sub>O<sub>3</sub>

**Table 5.** Composition of the amorphous grain boundary phases measured by EDAX

Element	wt%	Oxide%
Al	9.26	17.50
Si	29.40	62.91
Ca	8.00	11.20
Y	4.43	5.63
Zr	2.48	3.35





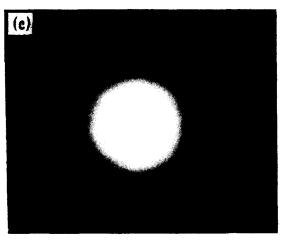


Fig. 4. Transmission electron micrographs of the amorphous grain boundary phases. (a), (b) Bright field images, (c) SADP. The arrows indicate the grain boundary phases.

is dissolved in ZrO<sub>2</sub> grains; (2) the surplus Al<sub>2</sub>O<sub>3</sub> then forms Al<sub>2</sub>O<sub>3</sub> particles, which are extensively situated intra- and intergranularly; (3) Al<sub>2</sub>O<sub>3</sub> segregates at grain boundaries, and forms the crystal and the amorphous Al-rich grain boundary phases; the amorphous one contains impurities such as Si and Ca.

#### 4 Discussions

# 4.1 Effect of Al<sub>2</sub>O<sub>3</sub> on the grain boundary resistance of ZrO<sub>2</sub>

 $Al_2O_3$  can reduce the  $ZrO_2$  grain boundary resistance. Butler & Drennan suggested that this is because that  $Al_2O_3$  acts as a scavenger for  $SiO_2$  located at grain boundaries.<sup>13</sup> There are two types of grain boundary phases in  $ZrO_2$ , the crystal and the amorphous. Table 2 shows that the  $ZrO_2$  grain boundary resistance is controlled by the  $Al_2O_3$  addition and that  $Al_2O_3$  reduces the  $R_{gbs}$ . This phenomenon may be explained with two mechanisms that are related to the two types of grain boundary phases.

Mechanism I: the Al<sub>2</sub>O<sub>3</sub> addition scavenges SiO<sub>2</sub> located at grain boundaries and results in a low grain boundary resistance. This is similar to the results of Butler & Drennan. The only difference from the experiment of Butler & Drennan is that the specimens used in this paper contain CaO as well as SiO<sub>2</sub>. According to the CaO-Al<sub>2</sub>O<sub>3</sub>-SiO<sub>2</sub> phase diagram, <sup>14</sup> CaO, Al<sub>2</sub>O<sub>3</sub> and SiO<sub>2</sub> with a concentration relation listed in Table 5 will react with each other according to the following equation:

$$CaO + Al_2O_3 + 2SiO_2 \rightarrow CaAl_2Si_2O_3$$
 (5)

The impurities CaO and SiO<sub>2</sub> are transported by grain boundary diffusion to the triple points with high Al<sub>2</sub>O<sub>3</sub> concentration and the Al<sub>2</sub>O<sub>3</sub> particle surface, and by the chemical reaction (5), the grain boundary impurities are scavenged, and as a result,  $E_{\rm gb}$  decreases.

Mechanism II: The crystal grain boundary phases contain no CaO or SiO<sub>2</sub>, so the mechanism I can not explain all the experimental phenomena. And besides, the positron annihilation results show that Al<sub>2</sub>O<sub>3</sub> increases the crystal defect concentration in ZrO2. The defects can be roughly divided into two main parts, the defects in grains and those in the crystal grain boundary phases. The defects in grains are determined by the dopant Y<sub>2</sub>O<sub>3</sub>, and the Al<sub>2</sub>O<sub>3</sub> solubility in grains is very low, so the effect of Al<sub>2</sub>O<sub>3</sub> on the grain defects is negligible. This means that the increased crystal defect concentration is a result of the increasing of crystal defects in the crystal grain boundary phases, and consequently the resistance of the crystal grain boundary phases is very low, so the  $R_{\rm gbs}$  subsequently decreases. Thus a new mechanism is derived as follows: the Al<sub>2</sub>O<sub>3</sub> segregated at grain boundaries forms crystal grain boundary

phases with very high defect concentration, so the grain boundary resistance decreases. Aono and coworkers observed a somewhat similar phenomenon in the solid electrolyte based on LiTi<sub>2</sub>(PO<sub>4</sub>)<sub>3</sub><sup>15,16</sup> in which grain boundary conductivity increases considerably by adding Li<sub>3</sub>BO<sub>3</sub> or Li<sub>4</sub>P<sub>2</sub>O<sub>7</sub>. The reason for the conductivity enhancement was attributed to the enhancement of the lithium concentration at the grain boundaries and the formation of a new conductive phase at the grain boundaries.

It should be noted that the enhancement of the ionic conductivity of some compounds by the incorporation of fine non-conduction particles seems to be quite popular, 17,18 It was usually considered to be due to the formation of conductive, defectrich interfaces. This explanation is not quite applicable to the phenomena observed in this study, because Fig. 1(d) shows that the intragranular Al<sub>2</sub>O<sub>3</sub> particles are accompanied by pores, and no such defect-rich interfaces were found for them, only for the intergranular Al<sub>2</sub>O<sub>3</sub> particles, where such defect-rich interfaces were observed. So it must be stressed that the inter- and intragranular particles have different effects on the conductivity, when there are large difference in properties between the particles and the matrix, the conductive, defect-rich interfaces can only form for the intergranular particles.

# 4.2 Effect of grain boundaries on the emf of the ZrO<sub>2</sub> oxygen sensor

As an oxygen ion conductor, ZrO<sub>2</sub> is popularly used in oxygen sensors. By the emf output of the oxygen sensor, the oxygen partial pressure in all kinds of atmospheres can be measured. There are lots of factors affecting the emf output, the principle ones are electrode structure, electrode/electrolyte interfaces and ZrO<sub>2</sub> microstructure. In a practical process of an oxygen sensor, all the above factors simultaneously bring about an influence, and it is almost impossible to differentiate the individual influences by experiments, therefore, the effect of the grain boundaries on the output of the ZrO<sub>2</sub> oxygen sensors is analysed with a simplified model as follows.

Figure 5 is a simplified schematic representation of an oxygen sensor containing grain boundary phases. Suppose  $t_i < 1$  for the grain boundary phases, because the current through the grain boundary phases is also carried by oxygen ions; apart from an increase of internal resistance, the grain boundary phases do not influence the exclusively ionic nature of the conductivity of  $ZrO_2$ . The emf of the oxygen sensor can be given by eqn (6), if the

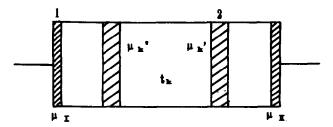


Fig. 5. Simplified schematic representation of an oxygen sensor. 1, Electrode; 2, grain boundary phases.

oxygen sensor is divided into several parts, as shown in Fig. 5. The meaning of  $t_k$ ,  $\mu_k''$  and  $\mu_k'$  can be seen from Fig. 5.

$$E = -\frac{1}{2ZF} \int_{\mu_{l}}^{\mu_{ll}} t \, d\mu$$
$$= -\frac{1}{2ZF} \sum_{k} t_{k} (\mu_{k}^{"} - \mu_{k}^{"})$$
 (6)

When  $t_k = 1$ , the chemical potential of the region k can be totally transferred into the emf; when  $t_k < 1$  and  $\mu_k'' - \mu_k' = 0$ , or  $t_k = 0$  and  $\mu_k'' - \mu_k' \neq 0$ , the region k does not make any contribution to the emf. Under this condition,  $E = E_{\text{th}}$  is held true,  $E_{\text{th}}$  being the theoretical value. When  $t_k < 1$  and  $\mu_k'' - \mu_k' \neq 0$ , then  $E < E_{\text{th}}$ . When oxygen partial pressures over the electrodes are changed, during a transient situation, an appreciable oxygen potential drop may occur over the grain boundary phases, if  $t_k < 1$  this yields a deviation from the  $E_{\text{th}}$  and an emf drift. Because the chemical diffusion inside  $\text{ZrO}_2$  is very slow, the emf drift will last as long as several hours.

There are three kinds of grain boundary regions in the ZrO<sub>2</sub> with Al<sub>2</sub>O<sub>3</sub> addition, the 'clean' grain boundaries but with Al segregation, the grain boundaries with amorphous phases and the grain boundaries with crystal phases. As Kingery has pointed out,<sup>20</sup> the ionic nature of ceramic oxide always leads to the formation of an electrostatic potential on grain boundaries, the sign and magnitude of the electrostatic potential depending strongly on impurity concentration. The Al segregation at the 'clean' grain boundaries certainly will change the grain boundary electrostatic potential, so the  $\mu'_k$ ,  $\mu''_k$  values are changed, but although the nature of the 'clean' grain boundaries is unclear,  $t_i = 1$  will hold true from them, thus the 'clean' grain boundaries do not have a negative effect on the emf. For the amorphous grain boundary phase, supposing  $t_i = 0$  may be reasonable, and the amount of the amorphous phases is very limited, then according to this discussion the amorphous phases make no contribution to the emf. This means that the amorphous phases also do not have a negative effect on the emf. As proved by the present experiments, the crystal grain boundary phases are very conductive, and it can be seen from the Nernst-Einstein equation

$$D = \frac{\sigma KT}{CZ^2} \tag{7}$$

where D is the charge carrier's diffusivity, C is the concentration of charge carrier, Z the charge quantity, and K and T have their usual meanings, that the oxygen ion diffusivity in the crystal grain boundary phases is very high. As long as chemical diffusivity in the grain boundary phases is very high, there will be practically no oxygen concentration drop (that is, chemical potential drop) over these phases. Therefore, for the crystal grain boundary phases  $\mu_k'' - \mu_k' = 0$  might hold true, and then the phases will also possibly not have a negative effect on the emf of the oxygen sensor, notwithstanding that  $t_i = 1$  or  $t_i < 1$  for the crystal grain boundary phases. As the Al<sub>2</sub>O<sub>3</sub> addition can scavenge the grain boundary impurities, it can be concluded that the Al<sub>2</sub>O<sub>3</sub> segregation at the grain boundaries not only does not have a negative effect on the emf of the ZrO2 oxygen sensor but also can release, even wipe out the detrimental effects of the other impurities, e.g. SiO<sub>2</sub>.

#### 5 Conclusion

The Al<sub>2</sub>O<sub>3</sub> addition up to 5 mol% can reduce the grain boundary resistance per unit surface area of the grain boundaries and the activation energy for the grain boundary resistance of the 9 mol% Y<sub>2</sub>O<sub>3</sub>-stabilized ZrO<sub>2</sub>. This is due to the scavenging of the impurities segregated at the grain boundaries, e.g. SiO<sub>2</sub>, by Al<sub>2</sub>O<sub>3</sub> and the formation of the Al-rich crystal grain boundary phases with very high defect concentration. The Al<sub>2</sub>O<sub>3</sub> addition has no detrimental effect on the emf of the ZrO<sub>2</sub> oxygen sensor. All of this proves that the Al<sub>2</sub>O<sub>3</sub>-containing Y<sub>2</sub>O<sub>3</sub>-stabilised ZrO<sub>2</sub> is a kind of very good solid electrolyte and that to decrease the grain boundary resistance by adding new ingredients is a feasible way to further enhance the ionic conduction of ZrO2. The next step that should be taken is to explore more oxides with characteristics similar to Al<sub>2</sub>O<sub>3</sub>.

#### References

- Yen, T. S., The microstructure and properties of ceramics.
  The development of ceramic microstructure and modern methods of investigation. J. Chin. Ceram. Soc., 9 (1981) 64-79.
- Badwal, S. P. S. & Drennan, J., Yttria-zirconia: effect of microstructure on conductivity. J. Mat. Sci., 22 (1987) 3231-9.
- Etsell, T. H. & Flengas, S. N., The electrical properties of solid oxide electrolyte. Chem. Rev., 70 (1970) 339-76.
- 4. Badwal, S. P. S & Hughes, A. E., The effects of sintering

- atmosphere on impurity phase formation and grain boundary resistivity in  $Y_2O_3$ -fully stabilized  $ZrO_2$ . J. Eur. Ceram. Soc., 10 (1992) 115–22.
- Keiger, K., Burggraaf, A. J. & De With, G., The effect of Bi<sub>2</sub>O<sub>3</sub> on the electrical and mechanical properties of ZrO<sub>2</sub>-Y<sub>2</sub>O<sub>3</sub> ceramics. J. Mat. Sci., 17 (1982) 1095-102.
- 6. Verkerk, M. J., Winnubst, A. J. A. & Burggraaf, A. J., Effect of impurities on sintering and conductivity of yttria-stabilized zirconia. J. Mat. Sci., 17 (1982) 3113–22.
- Radford, K. C. & Bratton, R. J., Zirconia electrolyte cells. Part 1. Sintering studies. J. Mat. Sci., 14 (1979) 59-65.
- Miyayama, M., Yanagida, H. & Asada, A., Effects of Al<sub>2</sub>O<sub>3</sub> additions on resistivity and microstructure of yttria-stabilized zirconia. Am Ceram. Soc. Bull., 65 (1985) 660-4
- Bauerle, J. E., Study of solid electrolyte polarization by a complex admittance method. J. Phys. Chem. Solids, 30 (1969) 2657-70.
- Miyayama, M. & Yanagida, H., Dependence of grain-boundary resistivity on grain-boundary density in yttria-stabilized zirconia. J. Am. Ceram. Soc., 67 (1984) C194-5.
- Brandt, W. & Dupasquier, A., Positron Solid State Physics. North Holland, Amsterdam, 1983, p. 24, p. 200.
- 12. Bernard, H., Sintered stabilized zirconia microstructure

- and conductivity. Report CEA-R-5090, Commissariat à l'Energie Atomique, CEN-Saclay, France, 1981, p. 117.
- Butler, E. P. & Drennan, J., Microstructural analysis of sintered high-conductivity zirconia with Al<sub>2</sub>O<sub>3</sub> additions. J. Am. Ceram. Soc., 65 (1982) 474-8.
- Gottwald, G., Forkel, K. & Wihsmann, F. G., Computer assisted design of phase diagrams. Silikattechnik, 36 (1985) 49-53.
- 15. Aono, H. & Sugimoto, E., Ionic conductivity of solid electrolytes based on lithium titanium phosphate. J. Electrochem. Soc., 137 (1990) 1023-7.
- Aono, H., Sugimoto, E., Sadaoka, Y., Imanaka, N. & Adachi, G., Ionic conductivity of LiTi<sub>2</sub>(PO<sub>4</sub>)<sub>3</sub> mixed with lithium salts. *Chem. Lett.*, 219 (1991) 331-4.
- 17. Liang, C. C., Conduction characteristics of the lithium iodide-aluminum oxide solid electrolytes. *J. Electrochem. Soc.*, **120** (1973) 1289–92.
- Jow, T. & Wagner, Jr, J. B., The effect of dispersed alumina particles on the electrical conductivity of cuprous chloride. J. Electrochem. Soc., 126 (1979) 1963-72.
- Beekmans, N. M & Heyne, L., Correlation between impedance microstructure and composition of calciastabilized zirconia. *Electrochem. Acta*, 12 (1976) 303-10.
- Kingery, W. D., Plausible concepts necessary and sufficient for interpretation of ceramic grain-boundary phenomena:
   Grain-boundary characteristics, structure, and electrostatic potential. J. Am. Ceram. Soc., 57 (1974) 1-8.